

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/808,786	HEAVLIN, WILLIAM D.	
	Examiner	Art Unit	Page 1 of 2
Arunkumar P Mehta	2128		

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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B	US-6,708,073	03-2004	Heavlin, William D.	700/121
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L	US-			
M	US-			

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V	Heavlin et al ("Dual Space Algorithms for Designing Space-Filling Experiments", 1994)	
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X	Wynn ("The Sequential Generation of D-optimum Experimental Designs", 1970)	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	X	

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